



<b>[WE4] Nano Devices Using 2D Materials IV</b>	
<b>Date / Time</b>	July 25 (Wed.), 2018 / 17:00-18:30
<b>Place</b>	Room E (#107~108)
<b>Session Chair(s)</b>	Young Chul Choi (KCTECH, Korea)

**WE4-1 [Invited] 17:00-17:30**

Normalization of Work Function of a Conducting Tip for Electrical Scanning Probe Microscopy (ESPM)  
Haeseong Lee, Inseob Im, and Jongjun An  
*Jeonju Univ., Korea*

**WE4-2 [Invited] 17:30-18:00**

Protocol for the Electrical Characterization of Powder-Type Graphene Materials  
Ha-Jin Lee<sup>1</sup>, Ji Sun Kim<sup>1</sup>, Haeseong Lee<sup>2</sup>, Kyung Ho Park<sup>3</sup>, and Mahfuza Mubarak<sup>1</sup>  
<sup>1</sup>*Korea Basic Science Inst., Korea*, <sup>2</sup>*Jeonju Univ., Korea*, <sup>3</sup>*Korea Advanced Nano Fab Center, Korea*

**WE4-3 [Invited] 18:00-18:30**

Measurement of EMI Shielding Effectiveness with Near Field Probe for CNT  
Soon Il Yeo  
*ETRI, Korea*